

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Assistant Commissioner for Patents
Washington, DC 20231

Re: **Patents and Patent applications for**
Leica Microsystems International Holdings GmbH

Sir:

REVOCATION AND GRANT OF POWER OF ATTORNEY

Applicant hereby revokes all powers of attorney previously granted for the patents and patent applications listed below and appoints as its attorneys or agent, with full power of substitution and revocation, to prosecute the patents and patent applications and to transact all business in the United States Patent and Trademark Office connected therewith:

Mark S. Leonardo	Reg. No. 41,433	Peter B. Sorell	Reg. No. 44,349
Brian L. Michaelis	Reg. No. 34,221	Mark A. Hofer	Reg. No. 30,068
David D. Lowry	Reg. No. 38,538	Barry C. Nelson	Reg. No. 46,951
Joseph P. Quinn	Reg. No. 45,029	John P. Serio	Reg. No. 39,023
Maria M. Eliseeva	Reg. No. 43,328	Lucy Elandjian	Reg. No. 46,164
John J. Penny, Jr.	Reg. No. 36,984		

All of Brown, Rudnick, Freed & Gesmer, One Financial Center, Boston, MA 02111

Serial No.	Filing Date	Patent No.	Title
09/476,649	12/31/1999		Method and System for Compensating Intensity Fluctuations of an Illumination System in a Confocal Microscope
09/476,589	12/31/1999		Method and System for Processing Scan-Data from a Confocal Microscope
09/476,588	12/31/1999		Method and System for User Guidance in Scanning Microscopy
09/439,876	11/12/1999		Refractometer and Method for Qualitative and Quantitative Measurements
09/678,129	10/04/2000		Device for Changing Lenses in a Microscope with a Fixed Stage
09/676,836	09/29/2000		Refractometer for Monitoring Water Content in Fluids
09/681,008	11/15/2000		Apparatus for Optical Scanning of Multiple Specimens
09/681,014	11/20/2000		Apparatus for Beam Deflection
09/681,019	11/28/2000		Method for Optical-Light Scanning of a Specimen and Scanning Microscope for Scanning a Specimen
09/708,778	11/08/2000		Method and Apparatus for Measuring Thickness of

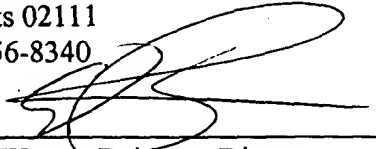
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09/681,051	12/10/2000		Microscope and Method for Analyzing Acquired Scan Data
09/681,109	01/10/2001		Arrangement for Detecting Fluorescent Light from a Plurality of Sample Points
09/681,186	02/14/2001		Method for Examining Structures on a Semiconductor Substrate
09/825,273	04/03/2001		Apparatus for Combining Light and Confocal Scanning Microscope
09/826,712	04/05/2001		Double Confocal Scanning Microscope
09/097,368	06/15/1998	5,969,808	Brake Check Handheld Refractometer
09/238,547	01/28/1999	6,034,762	Brake Check Handheld Refractometer
09/464,559	12/16/1999		Displaceable x/y Coordinate Measurement Table
09/681,096	01/04/2001		Measuring Instrument and Method for Measuring Features on a Substrate
60/142,207	07/02/1999		Refractometer and Method for Sensitive and Quantitative Measurements
60/108,414	11/13/1998		Refractive Index Based on Biosensor Device
60/157,436	10/04/2000		Device for Changing Lenses in a Microscope with a Fixed Stage
60/182,375	02/14/2000		Method for Examination of Operable Integrated and non-integrated Electronic Circuits
60/054,330	07/31/1997		Brake Check Handheld Refractometer
60/176,284	01/14/2000		Apparatus and Method for Determining Structures on a Substrate
60/170,243	12/10/1999		System and Method for Evaluation Registered Scan Data and a Scanning Fluorescent Microscope with a method for Evaluation Registered Scan Data
60/164,162	11/08/1999		Method and Device for Measuring The Thickness of Transparent Layers

Applicant hereby requests that all correspondence be directed to

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Dated: May 29/2001


Dr. Werner Retchert, Director
Corporate Patent and Trademark Department